捷多邦,专业PCB打样工厂**SN54时0153**5SN74HC153 **DUAL 4-LINE TO 1-LINE DATA SELECTORS/MULTIPLEXERS**

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- Permit Multiplexing from n Lines to One Line
- Perform Parallel-to-Serial Conversion
- Strobe (Enable) Line Provided for Cascading (N Lines to n Lines)
- **Package Options Include Plastic** Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

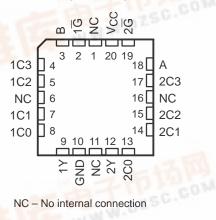
Each of these data selectors/multiplexers contains inverters and drivers to supply full binary decoding data selection to the AND-OR gates. Separate strobe (\overline{G}) inputs are provided for each of the two 4-line sections.

The SN54HC153 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC153 is characterized for operation from -40°C to 85°C.

SN54HC153...J OR W PACKAGE SN74HC153...D, N, OR PW PACKAGE (TOP VIEW)



SN54HC153 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE

	1	400	INPUTS					
SEL	ECT†	60	DA	DATA			OUTPUT	
В	Α	C0	C1	C2	C3	G		
Х	X	Х	Х	Х	Х	Н	L	
L	L	L	Χ	X	X	L	L	
L	L	Н	Χ	X	X	L	Н	17.10
L	Н	Х	L	X	X	L	L	工行物作
L	Н	Х	Н	X	X	L	Н	DISC.GO
Н	L	Х	Χ	L	X	L	L val	M.M.P.
Н	L	Х	Χ	Н	X	L	Н	
Н	Н	X	Χ	X	L	L	L	
Н	Н	X	X	X	Н	L	Н	

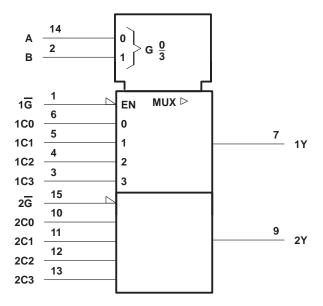
Select inputs A and B are common to both sections.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



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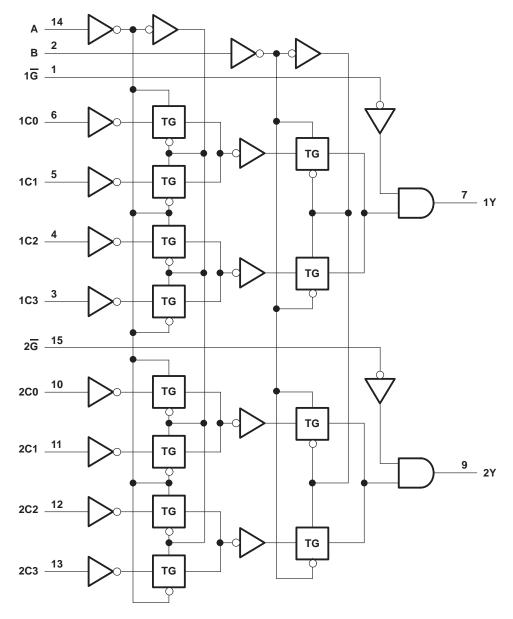
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.



logic diagram (positive logic)



Pin numbers shown are for the D, J, N, PW, and W packages.

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absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}		0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see	ee Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CO}$	c) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±35 mA
Continuous current through V _{CC} or GND		±70 mA
Package thermal impedance, θ _{JA} (see Note 2)	: D package	113°C/W
,		
	PW package	149°C/W
Storage temperature range, T _{stq}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			SI	N54HC15	53	SI	174HC15	3	UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC	Supply voltage		2	5	6	2	5	6	V	
		V _{CC} = 2 V	1.5			1.5				
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15		3.15 4.2 0.5 0 0.5 1.35 0 1.35	V				
		VCC = 6 V	4.2			4.2				
		V _{CC} = 2 V	0		0.5	0		0.5	V	
V_{IL}	Low-level input voltage	V _{CC} = 4.5 V	0		1.35	0		1.35		
		V _{CC} = 6 V	0		1.8	0		1.8		
٧ _I	Input voltage		0		Vcc	0		VCC	V	
٧o	Output voltage		0		Vcc	0		VCC	V	
		V _{CC} = 2 V	0		1000	0		1000		
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500	ns	
		V _{CC} = 6 V	0		400	0		400		
T _A	Operating free-air temperature	•	-55		125	-40		85	°C	



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	MULTIONS	Vcc	Т	A = 25°C	;	SN54H	IC153	SN74H	C153	UNIT		
PARAMETER	lesi cc	, COMBINIONS		TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9				
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4				
Voн	$V_I = V_{IH}$ or V_{IL}		6 V	5.9	5.999		5.9		5.9		V		
		I _{OH} = -6 mA	4.5 V	3.98	4.3		3.7		3.84				
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34				
			2 V		0.002	0.1		0.1		0.1			
		I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1 0.1 0.1 0.1	0.1				
VOL	$V_I = V_{IH} \text{ or } V_{IL}$		6 V		0.001	0.1		0.1		0.1	V		
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33			
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.1 0.1 0.1 0.33 0.33 ±1000			
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA		
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ		
Ci			2 V to 6 V		3	10		10		10	pF		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	չ = 25°C	;	SN54H	IC153	SN74H	IC153	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	01411	
			2 V		90	150		225		190		
	A or B	Υ	4.5 V		21	30		45		38		
			6 V		17	26		38		32	ns	
	Data (Any C)	Y	2 V		73	126		189		158		
t _{pd}			4.5 V		17	28		42		35		
	(7 tily 3)		6 V		14	23		35		29		
			2 V		38	95		150		125		
	G	Υ	4.5 V		11	19		28		24		
			6 V		9	16		24		MAX 190 38 32 158 35 29 125		
			2 V		20	60		90		75		
t _t		Υ	4.5 V		8	12		18		190 38 32 158 35 29 125 24 20 75	ns	
			6 V		6	10		15		13		

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switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	TA	√ = 25°C	;	SN54H	C153	SN74H	IC153	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
			2 V		105	235		355		295	
	A or B	Υ	4.5 V		27	47		71		59	
			6 V		21	41		60		51	
			2 V		93	220		335		274	
^t pd	Data (Any C)	Y	4.5 V		23	44		67		55	ns
			6 V		19	38		57		48	
	G	Y	2 V		60	185		280		230	
			4.5 V		17	37		56		46	
			6 V		14	32		48		40	
			2 V		45	210		315		265	
t _t		Y	4.5 V		17	42		63		53	ns
			6 V		13	36		53		45	

operating characteristics, T_A = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per multiplexer	No load	40	pF

PARAMETER MEASUREMENT INFORMATION ۷сс **From Output** Test 50% Input 50% **Under Test Point** Cı **tPLH** - tPHL (see Note A) In-Phase 90% 50% Output **LOAD CIRCUIT** VOL **▼** tPHL ^tPLH **VCC** Input 50% 90% Out-of-Phase 50% 10% 0 V 10% Output **VOLTAGE WAVEFORM VOLTAGE WAVEFORMS** INPUT RISE AND FALL TIMES PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_\Gamma = 6 \ ns$, $t_f = 6 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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